

4 Amps, 700 Volt N-CHANNEL POWER MOSFET

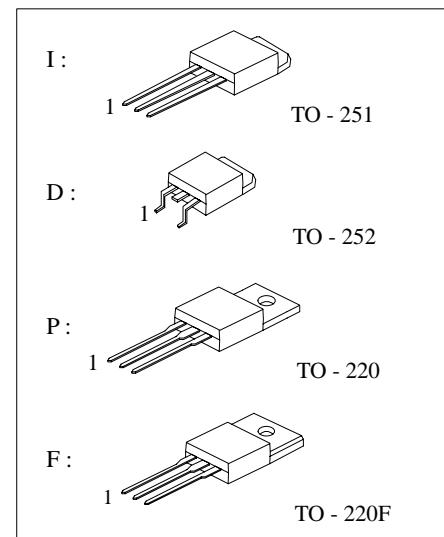
■ DESCRIPTION

The FTK4N70 is a high voltage MOSFET and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristics. This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient DC to DC converters and bridge circuits.

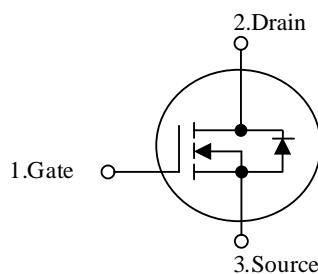
■ FEATURES

- * $R_{DS(ON)} = 2.7\Omega @ V_{GS} = 10V$
- * Ultra low gate charge (typical 15 nC)
- * Low reverse transfer Capacitance ($C_{RSS} = \text{typical } 8.0 \text{ pF}$)
- * Fast switching capability
- * Avalanche energy Specified
- * Improved dv/dt capability, high ruggedness

Power MOSFET



■ SYMBOL



■ ORDERING INFORMATION

Ordering Number	Package	Pin Assignment			Packing
		1	2	3	
FTK4N70P	TO-220	G	D	S	Tube
FTK4N70F	TO-220F	G	D	S	Tube
FTK4N70I	TO-251	G	D	S	Tube
FTK4N70D	TO-252	G	D	S	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source



FTK4N70P/F/D/I

■ ABSOLUTE MAXIMUM RATINGS (T_C= 25°C, unless otherwise specified)

PARAMET		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V _{DSS}	700	V
Gate-Source Voltage		V _{GSS}	±30	V
Avalanche Current (Note 1)		I _{AR}	4.4	A
Continuous Drain Current	T _C = 25°C	I _D	4.0	A
	T _C = 100°C		2.5	
Pulsed Drain Current (Note 1)		I _{DM}	16	A
Avalanche Energy	Single Pulse(Note 2)	E _{AS}	260	mJ
	Repetitive Limited by T _{J(MAX)}	E _{AR}	10.6	mJ
Peak Diode Recovery dv/dt (Note 3)		dv/dt	4.5	V/ns
Total Power Dissipation (TO-251/252/TO-220F/220)	T _c =25 °C	P _D	45/45/31/62.5	W
			Derate above 25°C	0.36/0.36/0.25/0.5
Junction Temperature		T _J	+150	°C
Operating Temperature		T _{OPR}	-55 ~ +150	°C
Storage Temperature		T _{STG}	-55 ~ +150	°C

Note: Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

■ ELECTRICAL CHARACTERISTICS (T_C=25°C, unless Otherwise specified.)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} = 0V, I _D = 250μA	700			V
Drain-Source Leakage Current	I _{DSS}	V _{DS} = 700V, V _{GS} = 0V			10	μA
Gate-Source Leakage Current	Forward	I _{GSS}	V _{GS} = 30V, V _{DS} = 0V		100	nA
	Reverse		V _{GS} = -30V, V _{DS} = 0V		-100	nA
Breakdown Voltage Temperature Coefficient	ΔBV _{DSS} / ΔT _J	I _D = 250μA, Referenced to 25°C		0.6		V / °C
ON CHARACTERISTICS						
Gate Threshold Voltage	V _{GS(TH)}	V _{DS} = V _{GS} , I _D = 250μA	2.0		4.0	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} = 10V, I _D = 2.0A			2.7	Ω
Forward Transconductance	g _{FS}	V _{DS} = 50V, I _D = 2.0A (Note 4)		1.9		S
DYNAMIC CHARACTERISTICS						
Input Capacitance	C _{ISS}	V _{DS} = 25V, V _{GS} = 0V, f = 1.0MHz		520		pF
Output Capacitance	C _{OSS}			70		pF
Reverse Transfer Capacitance	C _{RSS}			8		pF
SWITCHING CHARACTERISTICS						
Turn-On Delay Time	t _{D(ON)}	V _{DD} = 350V, I _D =4.0A, R _G = 25Ω (Note 4,5)		13		ns
Turn-On Rise Time	t _R			45		ns
Turn-Off Delay Time	t _{D(OFF)}			25		ns
Turn-Off Fall Time	t _F			35		ns
Total Gate Charge	Q _G	V _{DS} = 560V, I _D = 4.0A, V _{GS} = 10V (Note 4,5)		15		nC
Gate-Source Charge	Q _{GS}			3.4		nC
Gate-Drain Charge	Q _{GD}			7.1		nC



■ ELECTRICAL CHARACTERISTICS(Cont.)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS						
Drain-Source Diode Forward Voltage	V _{SD}	V _{GS} = 0 V, I _S = 4.0 A			1.4	V
Maximum Continuous Drain-Source Diode Forward Current	I _S				4.4	A
Maximum Pulsed Drain-Source Diode Forward Current	I _{SM}				17.6	A
Reverse Recovery Time	t _{RR}	V _{GS} = 0 V, I _S = 4.0A,		250		ns
Reverse Recovery Charge	Q _{RR}	dI _F /dt =100 A/μs (Note 4)			1.5	μC

Note:

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2. L = 30mH, IAS = 4A, VDD = 50V, RG = 25 Ω, Starting TJ = 25°C
3. ISD≤ 4.4A, di/dt ≤200A/μs, VDD≤ BVDSS, Starting TJ = 25°C
4. Pulse Test: Pulse width ≤300μs, Duty cycle ≤ 2%
5. Essentially independent of operating temperature

■ TEST CIRCUITS AND WAVEFORMS

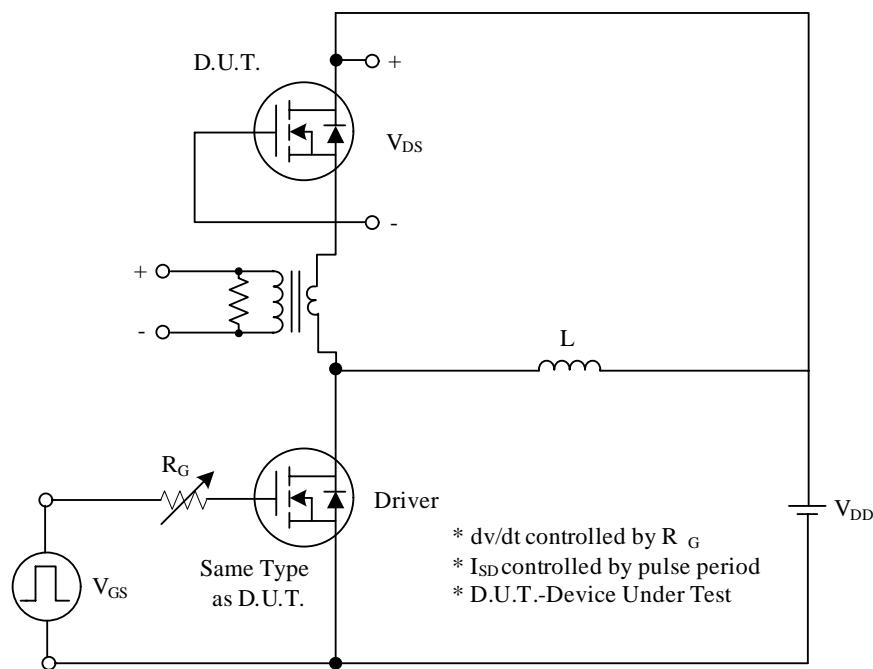


Fig. 1A Peak Diode Recovery dv/dt Test Circuit

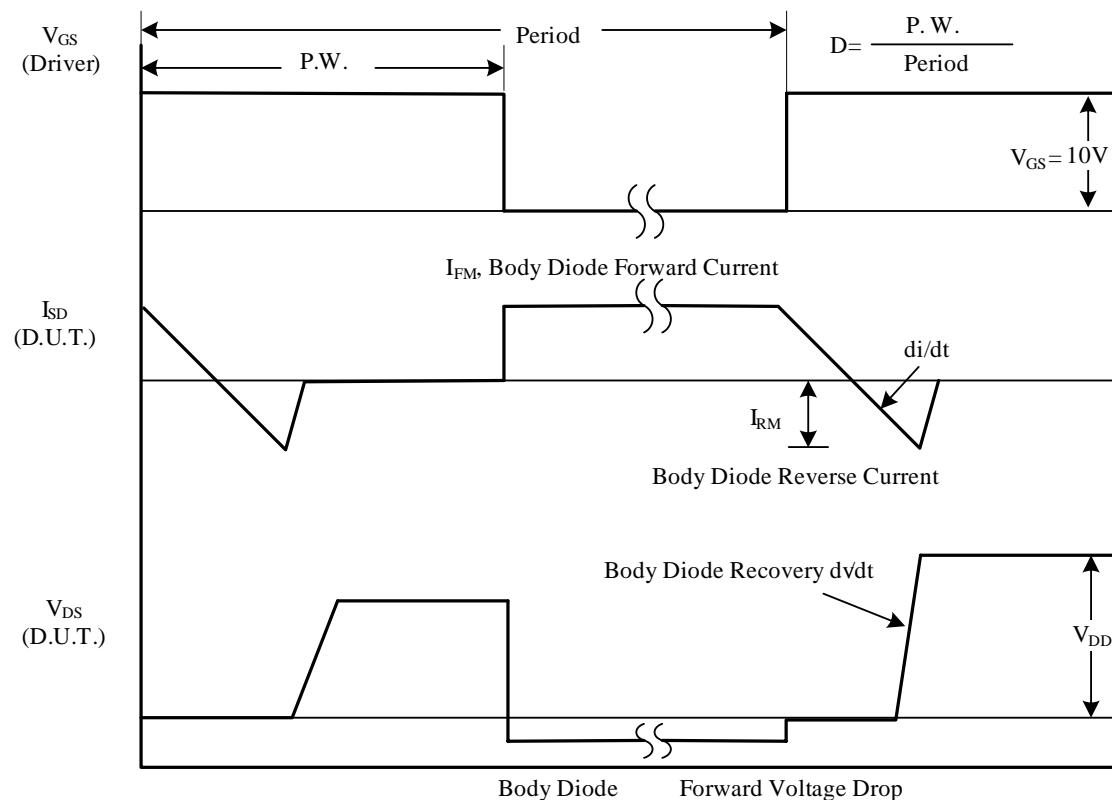


Fig. 1B Peak Diode Recovery dv/dt Waveforms

■ TEST CIRCUITS AND WAVEFORMS (Cont.)

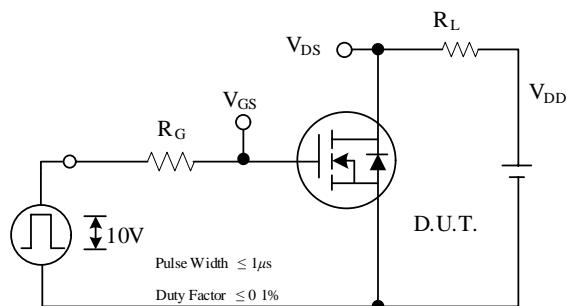


Fig. 2A Switching Test Circuit

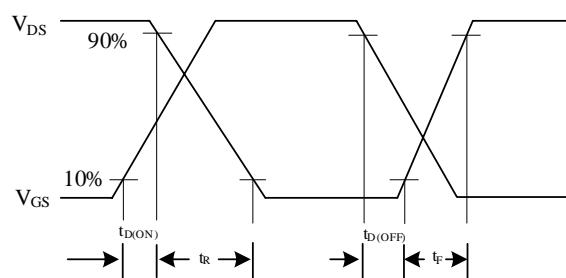


Fig. 2B Switching Waveforms

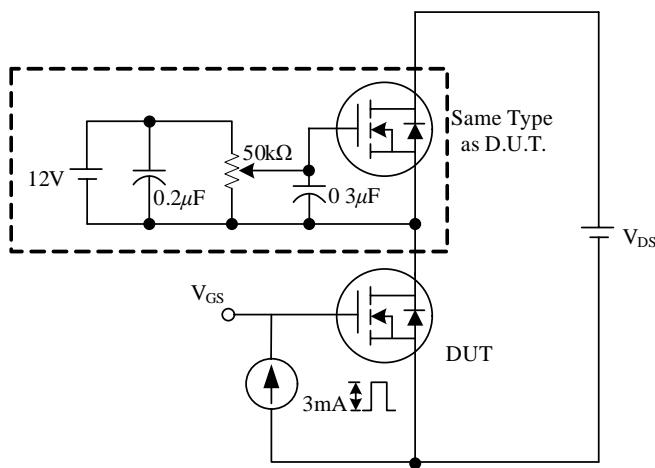


Fig. 3A Gate Charge Test Circuit

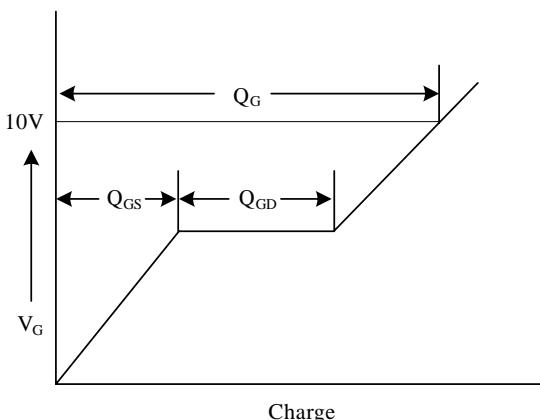


Fig. 3B Gate Charge Waveform

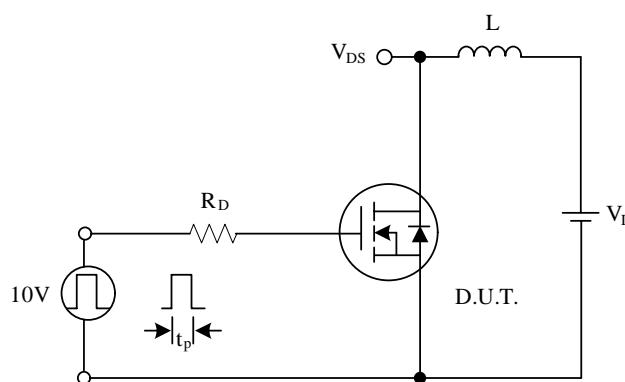


Fig. 4A Unclamped Inductive Switching Test Circuit

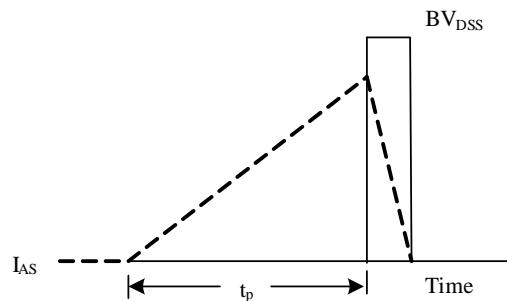


Fig. 4B Unclamped Inductive Switching Waveforms

■ TYPICAL CHARACTERISTICS

